Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/773,802	WON ET AL.
Examiner	Art Unit
Binh X. Tran	1765

SEARCHED				
Class	Subclass	Date	Examiner	
216	24	5/11/2006	вт	
216	72	5/11/2006	вт	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
Seach keywords and inventor's name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	5/10/2006	ВТ
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